

Session Title:	[Mo4E] Dimensional Metrology II
Session Date:	August 5 (Mon.), 2024
Session Time:	17:00-18:30
Session Room:	Room E (114)
Session Chairs	TBA

[Mo4E-1] [Invited] 17:00-17:30

Versatile Deflectometry Applications

Heejoo Choi, Daewook Kim, Roger Angel, Hubert M. Martin, Hyukmo Kang, and Yiyang Huang (Univ. of Arizona, USA)

[Mo4E-2] 17:30-17:45

Proof-of-Concept of Submillisecond-Temporal-Resolution 4D X-ray Tomography with Multibeam X-ray Imaging System

Wataru Yashiro, Xiaoyu Liang, Tadashi Abukawa (Tohoku Univ., Japan), Wolfgang Voegeli, Etsuo Arakawa (Tokyo Gakugei Univ., Japan), Tetsuroh Shirasawa (AIST, Japan), Kentaro Kajiwara (Japan Synchrotron Radiation Research Inst., Japan), and Hiroyuki Kudo (Univ. of Tsukuba, Japan)

[Mo4E-3] 17:45-18:00

Tomographic Imaging with Broadband Optical Noise Cancelling Using Antiphase Pulse by Phase-controlled Optical Frequency Comb

Takashi Kato, Keito Hino, Yasuhisa Nekoshima, Akifumi Asahara, and Kaoru Minoshima (The Univ. of Electro-Communications, Japan)

[Mo4E-4] 18:00-18:15

Reconstructing Three-Degree-of-Freedom Pose through Temporal Phase-Shifted Low-Coherence Spatial Interferograms

Liheng Shi (Yangtze Delta Region Inst. of Tsinghua Univ., Zhejiang, China), Jinxu Zhang (Tsinghua Univ., China), Yingying Gu, Fangqin Gai, Jing Liu (Beijing Inst. of Control Engineering, China), and Guanhao Wu (Tsinghua Univ., China)

[Mo4E-5] 18:15-18:30

Frequency-comb-referenced Plasmonic Phase Spectroscopy for Measurement of Spatial Distribution of Effective Refractive Index at a Nano Slit



Dae Hee Kim, Young Ho Park, Jun Hyung Park, Huy Hoang Chu, Seung-Woo Kim, and Young-Jin Kim (KAIST, Korea)